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ATTORNEY DOCKET NO.  
032350.B562 (TI-36727)

PATENT APPLICATION NO.  
10/749,886

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**In The United States Patent and Trademark Office**

In re Application of: Kartik (nmi) Ramanujachar  
Serial No.: 10/749,886  
Filing Date: December 31, 2003  
Title: *Wavelet Analysis of One or More Acoustic Signals to Identify  
One or More Anomalies in an Object*

**Mail Stop: Assignment Recordation Services**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Dear Sir:

**CERTIFICATE OF MAILING BY EXPRESS MAIL**

I hereby certify that this communication is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" under 37 C.F.R. § 1.10 on the date indicated below and is addressed to Commissioner For Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450.

*Willie Jiles*  
Willie Jiles

Date: February 18, 2004

Exp. Mail Receipt No. EV 324649460 US

**Information Disclosure Statement**

During the summer of 2002, while a student at Texas A&M University, Michael D. Dockins interned at Texas Instruments Incorporated ("TI") for course credit. Dr. Krzysztof Michalski of Texas A&M University was responsible for determining whether Mr. Dockins would receive course credit for his internship at TI. To receive course credit for his internship at TI, Mr. Dockins was required to submit a paper ("Paper") to Dr. Michalski detailing the project that Mr. Dockins undertook at TI. On August 9, 2002, Mr. Dockins submitted the Paper to Dr. Michalski for course credit for Mr. Dockins's internship at TI. The Paper is attached to this Information Disclosure Statement. An affidavit of Mr. Dockins and an affidavit of Dr. Michalski are also attached.

Before Mr. Dockins submitted the Paper, it was Mr. Dockins's understanding, based on discussions Mr. Dockins had with Dr. Michalski, that Dr. Michalski agreed to keep all information in the Paper confidential and not disclose any such information to any third party. Although Dr. Michalski does not recall specifically agreeing to not disclose any information in the Paper to any third party, Dr. Michalski had no intention of disclosing, and has not disclosed, any information in the Paper to any third party. Mr. Dockins submitted the Paper to Dr. Michalski only for purposes of receiving course credit for Mr. Dockins' internship at TI, and Dr. Michalski received and reviewed the Paper only for purposes of determining whether Mr. Dockins should receive course credit for Mr. Dockins's internship at TI.

Applicant makes no representation that a search has been made, that the Paper qualifies as prior art, or that the Paper is material to patentability.

Applicant submits this Information Disclosure Statement before a first Office Action on the merits. Therefore, under 37 C.F.R. § 1.97(b)(3), Applicant believes no fee is due. Nonetheless, the Commissioner is hereby authorized to charge any fee and credit any overpayment to Deposit Account No. 02-0384 of Baker Botts L.L.P.

Respectfully submitted,

BAKER BOTTS L.L.P.  
Attorneys for Applicant



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Christopher W. Kennerly  
Reg. No. 40,675

Date: February 18, 2004

**Customer Number: 23494**

PTO-1449

Application No.  
10749,886Applicant(s)  
Kartik (nmi) RamanujacharInformation Disclosure Citation  
In an ApplicationDocket Number  
032350.B562  
(TI-36727)

Group Art Unit

Filing Date  
December 31, 2003

## U.S. PATENT DOCUMENTS

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A						
B						
C						
D						
E						
F						
G						
H						

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
I							
J							
K							

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
L	Michael Dockins, Texas Instruments, Inc., "Frequency Domain Analysis of Time Domain Reflectometry Signals," 9 August 2002, 43 pages.	08/02/2002
M	Michael Dockins, "Affidavit of Michael D. Dockins," signed January 15, 2004, 2 pages.	01/15/2004
N	Dr. Krzysztof Michalski "Affidavit of Dr. Krzysztof Michalski," signed January 15, 2004, 2 pages.	01/15/2004
O		
P		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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